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transient current testing power supply

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[Issued patents](#)[Applications](#)Integrated circuit test power supply

US Pat. 5773990 - Filed Sep 29, 1995 - Megatest Corporation

One embodiment of a **power supply** for **testing** an integrated circuit includes a source ... This minimizes VDD changes when the DUT demands **transient current**,

...

Arrangement for transient-current testing of a digital electronic CMOS circuit

US Pat. 6414511 - Filed Feb 7, 2000 - Koninklijke Philips Electronics N.V.

Generally, **transient-current** measurements or so-called IDDT ... 38 that has an importantly unsymmetric **power supply** at +30 and -5 volts, respectively, ...

Apparatus for reducing power supply noise in an integrated circuit

US Pat. 6339338 - Filed Jan 18, 2000 - Formfactor, Inc.

An apparatus for limiting variation in **power supply** voltage at a **power** input ... in voltage results from a **transient current** the IC draws at its **power** input ...

Apparatus and method for defect testing of integrated circuits

US Pat. 6031386 - Filed Oct 31, 1997 - Sandia Corporation

\DDQ **testing** is based on the principle that CMOS ICs are designed to provide a very small quiescent **power supply current** drain due to leakage that is on the

...

Method and apparatus for performing operative testing on an integrated circuit

US Pat. 5929650 - Filed Feb 4, 1997 - Motorola, Inc.

As seen in the prior art, quiescent **current testing** is efficient in CMOS digital circuits ... of the **power supply** line of the device, Vdd. Referring to FIG. ...

Fast recovery power supply

US Pat. 4686462 - Filed Sep 26, 1985 - International Business Machines Corporation

Because capacitor 35 now recharges quickly the satu- **transient current** and quickly ... Thus, fast recovery **power supply**. the output 37 provides a measurable ...

System level latchup mitigation for single event and transient radiation ...

US Pat. 5672918 - Filed Aug 18, 1994 - The United States of America as represented by the United States Department of Energy

7D shows a typical **power supply** voltage. An arbitrary **power** dump period of 5 ... and **transient current** measurements were made on the +28 and +5 **power** buses ...

Apparatus and method for testing electrically controlled motor

US Pat. 4996477 - Filed Oct 26, 1989 - A.O. Smith Corporation

The portable test unit of claim 2, having a **power** lamp and a parallel **transient current** capacitor, switch connecting said test **power supply** to said selec- ...

Dynamic burn-in test equipment

US Pat. 6215324 - Filed Jan 5, 2000 - Nippon Scientific Co., Ltd.

For this reason, **current** detectors of the present invention are preferably inserted into both a higher level **power supply** line side and a lower level **power** ...

Integrated circuit fault testing implementing voltage supply rail pulsing ...

US Pat. 5483170 - Filed Aug 24, 1993 - New Mexico State University Technology Transfer Corp.

The pre-bias voltage will cause the **power supply** rails of the circuit to be tested to ... A simple **current** mirror detected the **transient current** (IDD) while ...

Voltage generating circuit for IC test

US Pat. 5594359 - Filed Jun 2, 1995 - Advantest Corporation

A voltage generating circuit for **testing** an IC device, comprising: 5 an ... amplifier and said **power supply** terminal for detecting a **current** flowing to said ...

Probe interface assembly

US Pat. 5144228 - Filed Apr 23, 1991 - International Business Machines Corporation

9, the capacitor 164 may be viewed 40 alternately as a **supply** of energy to provide **power** surges as required for **transient current** flow, or as a decoupling

...

Quiescent **current** monitor circuit for wafer level integrated circuit **testing**

US Pat. 5912562 - Filed Feb 4, 1997 - Motorola Inc.

As seen in the prior art, quiescent **current testing** is efficient in CMOS ... of the parasitic capacitance of the **power supply** line of the device, VDD. ...

Built-in **current testing** of integrated circuits

US Pat. 5025344 - Filed Feb 22, 1990 - Carnegie Mellon University

the comparator to disconnect **power** to the tested module when the quiescent ... and appears only during **transient current** peaks as an extra voltage drop ...

Rapid transit system **transient** voltage suppression apparatus

US Pat. 4322772 - Filed Mar 21, 1980 - Westinghouse Electric Corp.

5, and assuming a **power supply** having a maximum rated voltage of 720 volts and a **transient** fault **current** to be suppressed of 5000 amperes as shown by FIG. ...

Voltage sag/swell **testing** station

US Pat. 5886429 - Filed Dec 11, 1997 - Board of Regents, The University of Texas System

... 32 for **transient current** protection purposes. A master on-off control or bypass switch 50 is electrically connected by conductor 52 to the **power supply**

...

Method for fabricating integrated circuit (IC) dies with multi-layered ...

US Pat. 6423558 - Filed Feb 25, 2000 - Advantest Corporation

The quiescent **power supply current** test is a procedure which assumes a ... " Defect Detection with **Transient Current Testing** 35 and its Potential for Deep

...

Built-in test circuit for static CMOS circuits

US Pat. 5097206 - Filed Oct 5, 1990 - Hewlett-Packard Company

Low 36 is low and pass transistors 16 and 60 are conducting, **current** transistor 48 is ... If multiple **power** busses are required, the **Transient** behavior of ...

Clamp circuit to prevent ESD damage to an integrated circuit

US Pat. 6400540 - Filed Mar 11, 2000 - Silable Inc.

As the ESD event is a fast **transient** event, the peak ESD event **current** flowing

... In normal operation the **power supply** potential is greater than the ground

...

Quiescent power supply current test method and apparatus for integrated ...

US Pat. 5731700 - Filed Jun 19, 1996 - LSI Logic Corporation

1 2 QUIESCENT **POWER SUPPLY CURRENT** The output of the **current** sensor 12 is ... of

Field Effect Transistors (FET) that are arranged to con- high **transient** ...

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[Cover view](#)[Integrated circuit fault testing](#) implementing voltage supply rail pulsing ...

US Pat. 5483170 - Filed Aug 24, 1993 - New Mexico State University Technology Transfer Corp.

The pre-bias voltage will cause the power supply rails of the circuit to be tested to ... A simple current mirror detected the transient current (IDD) while

...

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[Sort by date \(new first\)](#)[Sort by date \(old first\)](#)[Fast recovery power supply](#)

US Pat. 4686462 - Filed Sep 26, 1985 - International Business Machines Corporation

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[Issued patents](#)[Applications](#)[Arrangement for transient-current testing](#) of a digital electronic CMOS circuit

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[Built-in current testing](#) of integrated circuits

US Pat. 5025344 - Filed Feb 22, 1990 - Carnegie Mellon University

the comparator to disconnect power to the tested module when the quiescent ... and appears only during transient current peaks as an extra voltage drop ...

Rapid transit system **transient** voltage suppression apparatus

US Pat. 4322772 - Filed Mar 21, 1980 - Westinghouse Electric Corp.

5, and assuming a **power supply** having a maximum rated voltage of 720 volts and a **transient fault current** to be suppressed of 5000 amperes as shown by FIG. ...

Quiescent **current testing** of dynamic logic systems

US Pat. 5557620 - Filed Sep 25, 1995 - Hewlett-Packard Company

Testing based on detecting an increase in **power supply current** is called quiescent ... **current** mea- 60 surement must be performed at a time when **transient** ...

Automatic controlled for an ice and snow melting system with ground **fault** ...

US Pat. 5710408 - Filed Aug 15, 1996 - MSX, Inc.

The heater 14 **supply** leads are 35 Operating the switch 98 causes the test ...

That is, unless a ground **fault current** the one-turn primary windings 74 and 76

...

Method and apparatus for performing operative **testing** on an integrated circuit

US Pat. 5929650 - Filed Feb 4, 1997 - Motorola, Inc.

As seen in the prior art, quiescent **current testing** is efficient in CMOS digital circuits ... of the **power supply** line of the device, Vdd. Referring to FIG. ...

Built-in test circuit for static CMOS circuits

US Pat. 5097206 - Filed Oct 5, 1990 - Hewlett-Packard Company

During the test mode, row **power** buss 18 is in ing state, the **current** ... the gates to switch states demands **transient current** pass transistor 28 in any ...

Integrated circuit **fault testing** system based on **power** spectrum analysis of ...

US Pat. 5949798 - Filed Feb 4, 1997 - NEC Corporation

1 2 INTEGRATED CIRCUIT **FAULT TESTING** transistor switching **current** in a CMOS ... there is **current** flows as the **supply current** except for **transient** 1S ...

Elevated voltage level l.sub.DDQ failure **testing** of integrated circuits

US Pat. 5519333 - Filed Sep 9, 1994 - Sandia Corporation

The **power supply** voltage level of the device must be the same level as 50 the logic level "1" for ... is an 60 arbitrary acronym for this **transient current**

...

Circuit breaker incorporating **fault** lockout protection

US Pat. 6657837 - Filed Dec 29, 1999 - General Electric Company

Electronic trip unit 51 senses **current** in **supply** line 104, ... thus eliminating the switching **transient current** on contact bypass lines 152, 154, 156. ...

Method and apparatus for **testing** an AFCI/GFCI circuit breaker

US Pat. 6426632 - Filed Apr 28, 2000 - George A. Spencer

A related technology developed to disable a **power** circuit in the event of a ground **fault** — typically an unintended leakage **current** path between a live ...

Device for preventive detection of faults with recognition of the type of load

US Pat. 5910875 - Filed Aug 5, 1997 - Schneider Electric SA

It then performs **fault** detection by measuring the **current** in the load when ... the **current** when the test **power supply** is constituted by a pulse generator. ...

Device for preventive detection of faults with identification of the type of ...

US Pat. 6081123 - Filed Oct 24, 1997 - Schneider Electric SA

It then performs **fault** detection by measuring the **current** in the load when ... the **current** when the test **power supply** is constituted by a pulse generator. ...

Redundant **power supply** and storage system

US Pat. 5747889 - Filed Jul 31, 1996 - Hewlett-Packard Company

5, a **power supply fault** indicates that the **current** sharing. ... adjusted for opti- Recovery of the **power supply** at issue is achieved by the mum **transient** ...

Quiescent **current** monitor circuit for wafer level integrated circuit **testing**

US Pat. 5912562 - Filed Feb 4, 1997 - Motorola Inc.

As seen in the prior art, quiescent **current testing** is efficient in CMOS ... of the parasitic capacitance of the **power supply** line of the device, VDD. ...

Semiconductor integrated circuit **fault** analyzing apparatus and method therefor

US Pat. 5521516 - Filed Dec 6, 1994 - NEC Corporation

4A, 4B, and 4C is called an automatic **power supply** ON-OFF method. ... and a voltage image (0.5 seconds) having 65 a small **transient** influence of a charge-up

...

High-voltage crowbar circuit with cascade-triggered series ignitrons

US Pat. 4232351 - Filed Jan 3, 1979 - The United States of America as represented by the United States Department of Energy

This **transient** overvoltage is reduced to to zero - Triggering of the circuit 10

... The hot air is in connection with a **power supply**, for **testing** of multi- ...

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[Cover view](#)Dynamic burn-in test equipment

US Pat. 6215324 - Filed Jan 5, 2000 - Nippon Scientific Co., Ltd.

And the difference causes **current** flows in the **test pattern** generator ...

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Therefore, when the currents flowing in the higher level **power supply** lines and[Sort by date \(new first\)](#)

...

[Sort by date \(old first\)](#)Semiconductor integrated circuit fault analyzing apparatus and method therefor

US Pat. 5521516 - Filed Dec 6, 1994 - NEC Corporation

› Any status

4A, 4B, and 4C is called an automatic **power supply** ON-OFF method. ... **test**[Issued patents](#)**pattern** from which an image is to be acquired to an entire **test vector** is[Applications](#)

defined ...

Integrated circuit test method and structure

US Pat. 5917331 - Filed Oct 23, 1995 - Megatest Corporation

Testing a CMOS device quiescent **power supply current** (IDDQ) is a useful ... Then, in step 304, a **test vector** is executed to bring DUT 106 to a known state. ...

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[Cover view](#)Elevated voltage level I.sub.DDQ failure testing of integrated circuits

US Pat. 5519333 - Filed Sep 9, 1994 - Sandia Corporation

The **power supply** voltage level of the device must be the same level as 50 the logic level "1" for ... is an 60 arbitrary acronym for this **transient current**

...

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[Sort by date \(new first\)](#)[Sort by date \(old first\)](#)Integrated circuit **fault** testing system based on **power** spectrum analysis of ...

US Pat. 5949798 - Filed Feb 4, 1997 - NEC Corporation

14 illustrates conceivable measurement of a quies- repetitive **test pattern** application and the **supply current** of cent **current** 105 caused as the **supply** ...

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[Issued patents](#)[Applications](#)Apparatus and method for defect testing of integrated circuits

US Pat. 6031386 - Filed Oct 31, 1997 - Sandia Corporation

After this, the **current** from the **power supply** will again settle down to the ... the quiescent **current**, \DDQ, as each **vector** in the set of **test** vectors is ...

Fast recovery **power supply**

US Pat. 4686462 - Filed Sep 26, 1985 - International Business Machines Corporation

1 illustrates in schematic form the CMOS **current** monitor **test** configuration of ... spike 17 occurs and both devices turn on producing a **transient current**, ...

Semiconductor integrated circuit **fault** analyzing apparatus and method therefor

US Pat. 5521516 - Filed Dec 6, 1994 - NEC Corporation

4A, 4B, and 4C is called an automatic **power supply** ON-OFF method. ... **test pattern** from which an image is to be acquired to an entire **test vector** is defined ...

Dynamic burn-in **test** equipment

US Pat. 6215324 - Filed Jan 5, 2000 - Nippon Scientific Co., Ltd.

And the difference causes **current** flows in the **test pattern** generator ...

Therefore, when the currents flowing in the higher level **power supply** lines and

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Generally, **transient-current** measurements or so-called IDDT ... 38 that has an

importantly unsymmetric **power supply** at +30 and -5 volts, respectively, ...

Method for fabricating integrated circuit (IC) dies with multi-layered ...

US Pat. 6423558 - Filed Feb 25, 2000 - Advantest Corporation

The quiescent **power supply current test** is a procedure which assumes a short-circuit **fault** across a plurality of signal lines in the circuit under **test** or a

...

Integrated circuit **test power supply**

US Pat. 5773990 - Filed Sep 29, 1995 - Megatest Corporation

Testing a CMOS device quiescent **power supply current** (IDDQ) is a useful ...

transient accumulated charge, and the device under **test power supply** 102 is set

...

Integrated circuit **test** method and structure

US Pat. 5917331 - Filed Oct 23, 1995 - Megatest Corporation

Testing a CMOS device quiescent **power supply current** (IDDQ) is a useful ... Then

, in step 304, a **test vector** is executed to bring DUT 106 to a known state. ...

Test method and apparatus using energy consumption ratio

US Pat. 6513137 - Filed Oct 18, 1999 - Cardiac Pacemakers, Inc., Regents of the University of Minnesota

This method includes connecting the circuit to a BACKGROUND **power supply**, ... to

the **supply** rails and measurement of the **transient vector** which maximizes NB ...

Fail safe architecture for a computer system

US Pat. 4726024 - Filed Mar 31, 1986 - Mieczyslaw Mirowski

2E, F and G. Assuming no **fault** is found by the self-check module in step, ...

the **current** data stored in that block of RAM, writing a first **test pattern** ...

High speed I.sub.DDQ monitor circuit

US Pat. 5694063 - Filed Sep 27, 1996 - LTX Corporation

The defects DUT provides the expected output for each **test vector**. ... 1C shows the behavior of the **power supply current** functional testing may not detect ...

High resolution (quiescent) **supply current** system (IDD monitor)

US Pat. 6118293 - Filed May 30, 1997

More in particular a system for **supply current** testing of an electronic device or ... The overall **test** cost of a circuit depends on the **test pattern** ...

Built-in **fault** testing of integrated circuits

US Pat. 5332973 - Filed May 1, 1992 - The University of Manitoba

Another advantage is that the circuit will after the **transient** is expected ... circuit under **test** as well as determine whether the quiescent circuit **current** ...

Location of a faulty pulse form restorer in a cable system

US Pat. 4220833 - Filed Sep 12, 1977 - The United States of America as represented by the Secretary of the Army

Resistor 10 would be inserted in series with the entire **power supply** string. ... wherein said **power** means is a constant **current** source; wherein said **fault** ...

Ground leakage relay circuit

US Pat. 4091431 - Filed Oct 9, 1970 - Harbey Hubbell, Incorporated

Under normal conditions, the **vector** sum of the the occurrence of a voltage of ... 30 includes a dc **power supply** such a short term **transient current** flow. ...

High or low-side state relay with **current** limiting and operational testing

US Pat. 4631474 - Filed Jul 11, 1984 - The United States of America as represented by the Secretary of the Air Force

1 2 built-in **test** indications during a specified **transient** HIGH OR LOW-SIDE STATE RELAY WITH ... The switch DC **power supply**. Schmidt, Jr. in US Pat. No. ...

High speed magnetic flux sampling

US Pat. 6118284 - Filed Oct 6, 1997

Characterizing **current** transients and Ldi/dt noise in the **power/ground/clock** distribution networks within the VLSI and high-performance chip/computer ...

Photon assisted tunneling testing of passivated integrated circuits

US Pat. 4644264 - Filed Mar 29, 1985 - International Business Machines Corporation

... using the "solar-cell" the **current transient** induced in the **power supply** by

... semiconductor solar cell for **fault** by- provides an improved extraction ...

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